

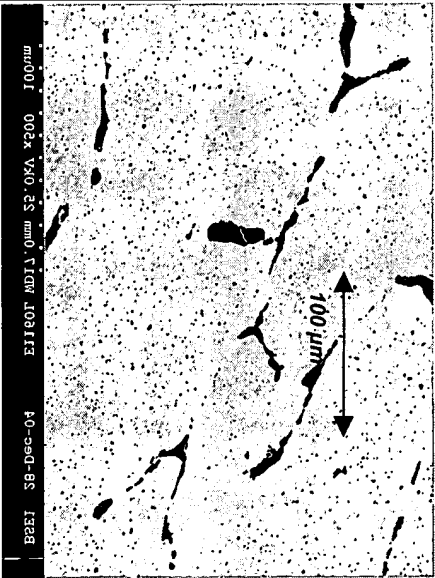
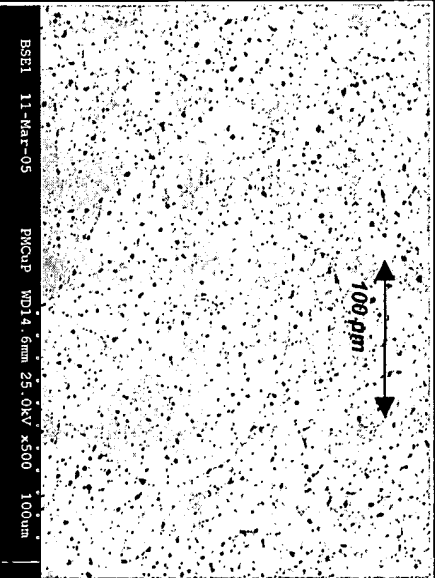
# US Patent Application 10/644,220

## Copper-Nickel-Silicon Two Phase Quench Substrate

Claim 1: A copper-nickel-silicon quench substrate of a thermally conducting alloy for rapid solidification of molten alloy into strip, having a two-phase microstructure with cells of copper rich regions surrounded intimately by a *discontinuous network* of nickel silicide and chromium silicide phases,

wherein said thermally conducting alloy is a copper-nickel-silicon alloy consisting essentially of about 6-8 wt. % nickel, about 1-2 wt. % silicon, about 0.3-0.8 wt. % chromium, the balance being copper and incidental impurities.

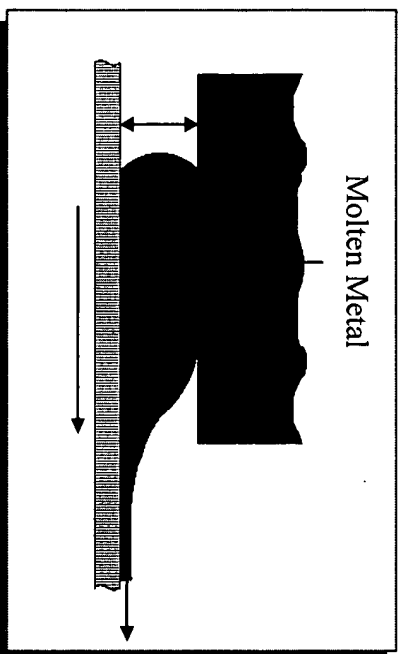
# Continuous Network vs Discontinuous Network

	Microstructure
<b>Continuous Network</b> Recrystallized or Dendrite Cu Grains ~ 100 $\mu\text{m}$ diameter Silicides at Boundaries      >100 $\mu\text{m}^2$ Silicides Within Cu grains      <5 $\mu\text{m}^2$  Cells Between Silicides      ~ 1000 $\mu\text{m}$	 <p>100 <math>\mu\text{m}</math></p> <p>mi001 002x Vx0.35 mm0.11Gm 109113 40-350-85 1324</p>
<b>Discontinuous Network</b> Cu Grains =      ~ 50 $\mu\text{m}$ diameter  Silicides at Boundaries      <5 $\mu\text{m}^2$ Silicides within Cu grains      <2 $\mu\text{m}^2$	 <p>100 <math>\mu\text{m}</math></p> <p>BSI1 11-Mar-05 PWCuP WD14.6mm 25.0kV x500 100um</p>

**Key:**  
 Black = CrSi  
 Dark Grey = NiSi  
 Light Grey = Cu

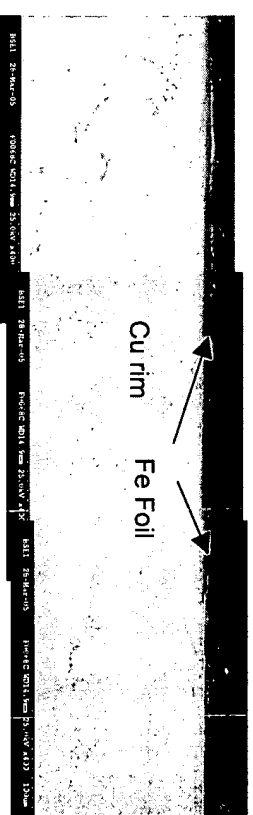
# Forces Acting on Rim

**Thermal Pulse** from casting molten metal onto the rotating rim



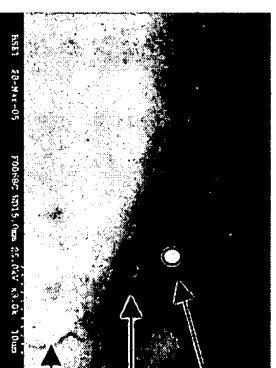
- Thermal Pulse Reduces Tensile Hoop Stress
- Average Rim Temperature ~ 300°C

**Peeling** from welding/stripping



EDS Analysis:

5.11Cr-25.99Fe-30.07Ni-38.82Cu



Ni-Silicide

Crack

- Molten Metal Penetrates Rim Surface (at large Silicides?)
- Cu, Cr and Ni Dissolution in Fe
- Cracks Extend From Weldment

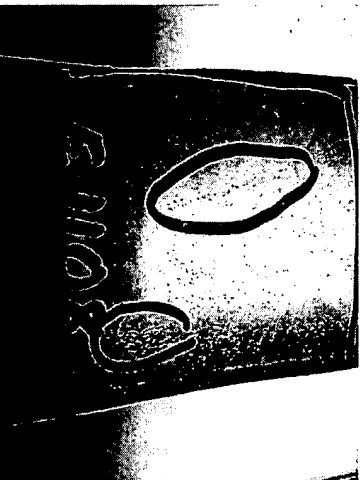
*Forces Acting on the Rim are not Traditional Mechanical Stresses*

# Rim Failure Modes

## Definitions:

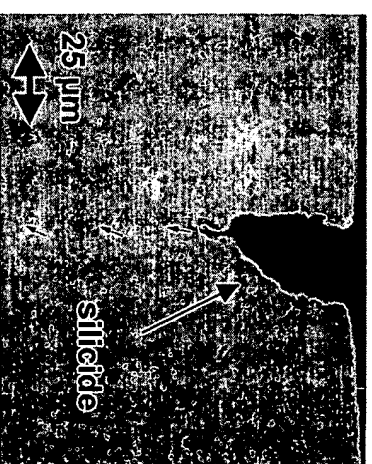
- **Pit**  
Rim defect caused by intergranular failure at the rim surface
- **Pip**  
Ribbon defect caused by casting over a pit
- **Pit Bands**  
Localized cluster of pits on the rim surface (typical in Cu-Be rims)
- **Scars**  
Localized cluster of pits on the rim surface (typical in Cu-Ni-Si-Cr rims)

**Macro of Rim Surface  
Showing Scars**



Note: Scarring is localized.  
Significant "good" area.

**Micro Cross Section of Rim  
Showing Pit and Silicides**

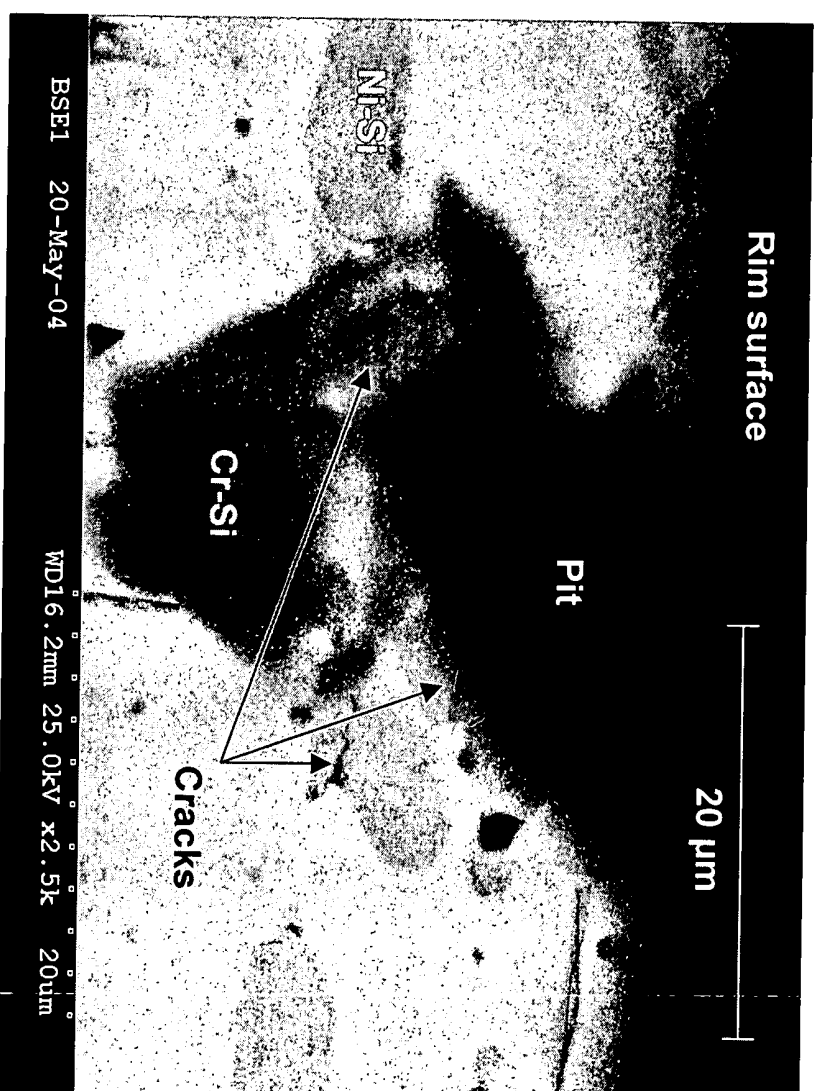


Note: Individual pit is small.  
Silicide is large (>5μm thick)

*Rim Failure Related to Non-Homogeneous Microstructure*

# Rim Surface Failure Analysis

## SEM – Transverse Section

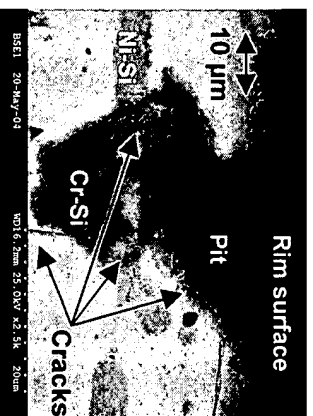


*Sub-surface Crack Networks Can Create Pits...  
Pits Can Expand Thru Continued Cracking*

# Continuous Network vs Discontinuous Network

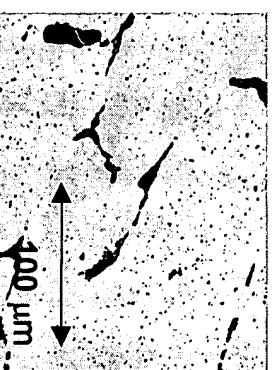
## General Rim Failure Mechanism

*Pit Formation via Crack Nucleation and Growth through Large Primary Silicides*

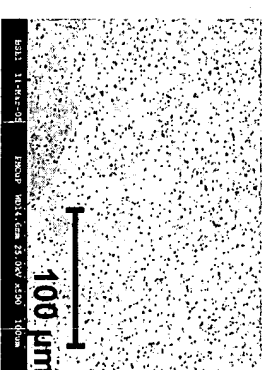


## Discontinuous Network Rims Have Reduced Silicide Size And Grain Size

Continuous Network Rim  
Grain Size ~ 100 μm  
Silicide Size up to 500 μm<sup>2</sup>



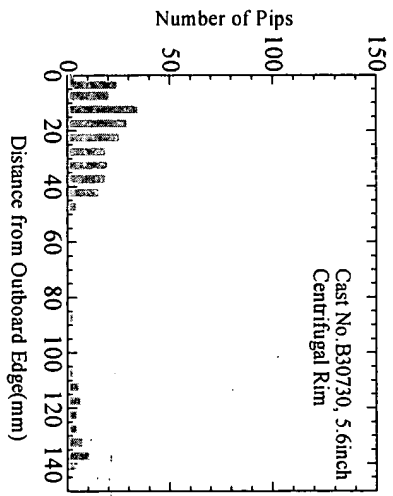
Discontinuous Network Rim  
Grain Size ~ 50 μm  
Silicide Size ~ 5 μm<sup>2</sup>



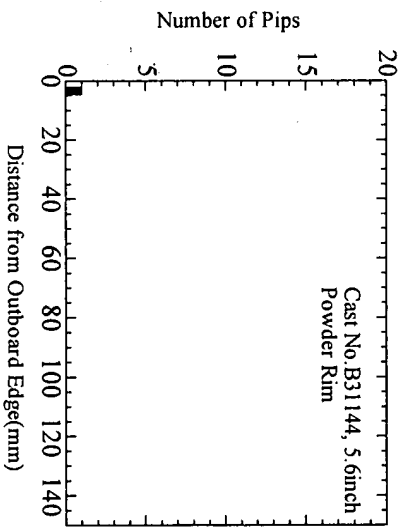
*Rim Surface Degrades via Cracking Through Large Silicide Particles  
No Large Silicide Particles in Discontinuous Network*

# Effect on Cast Strip Quality

Continuous Network  
Rim



Discontinuous Network  
Rim



More than 50 defects

Less than 5 defects

Discontinuous Network Rims Exhibit Reduced Defect Formation, Improved Quality